

Notice of References Cited	Application/Control No. 10/042,616		Applicant(s)/Patent Under Reexamination FLANAGAN, MARK J.	
	Examiner Trent J Roche		Art Unit 2124	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,199,193 B1	03-2001	Oyagi et al.	717/101
	B	US-5,537,618 A	07-1996	Boulton et al.	715/745
	C	US-5,706,452	01-1998	Ivanov, Vladimir I.	715/751
	D	US-2002/0133395 A1	09-2002	Hughes et al.	705/11
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Philip M. Johnson, "An Instrumented Approach to Improving Software Quality through Formal Technical Review", 1994, IEEE.
	V	J. Gintell, J. Arnold, M. Houde, J. Kruszelnicki, R. McKenney, G. Memmi, "Scrutiny: A Collaborative Inspection and Review System", 20 April 1993.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.